

10/068152

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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10068152	02/06/2002	324	765	2858	401-222

**APPLICANTS: Lee Sang-Eun; Han Jae-Sung; 2829

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 2001-8465 02/20/2001

Verified

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☒ yes ☐ no

35 USC 119 conditions met

☒ yes ☐ no

Verified and Acknowledged Examiners's initials

John - Hight

ATTORNEY DOCKET NO

8750-17

TITLE : Method of identifying and analyzing semiconductor chip defects

U.S. DEPT. OF COMM./PAT. & TM.-PTO-435L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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